

Micromegas TPC beam tests at KEK

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- •MPI TPC, Micromegas option
- •Beam test data taking
- Preliminary results
- •Future



Saclay, Orsay, Carleton, MPI, DESY, MSU, KEK, Tsukuba U, TUAT, Kogakuin U, Kinki U, Saga U (Canada, France, Germany, Japan, Philippines)

MPI TPC, Motivation

- Initiated by Ron Settles. Comparison of several gas amplifiers using same Field Cage, Electronics, analysis
 - MWPC : Beam test in Jun, 2004
 - GEM : Beam test in Apr, 2005
 - Micromegas

Beam test in Jun. 22 ~ Jul. 1, 2005



Micromegas



• S2

 Micromesh supported by 50-100µm high insulating pillars

50µm

- Multiplication takes place between the anode and the mesh
- One stage
- Direct detection of avalanche electrons
 - Small E×B effect
 - Fast signals
 - Self-suppression of positive ion feedback

the ions return to the grid

- Better potential spatial resolution
- No wire angular effect

Micromesh

Insulating substrate

The MPI TPC at KEK

- Drift length : 26 cm
- Pads
 - 2,3×6,3 mm pitches
 - 32 pads×12 pad rows
 ⇒ 384 readout channels
 - pad plane : 10×10 cm
- Readout
 - ALEPH TPC electronics
 - 24 amplifiers, 16 channels each 500ns shaping time, charge sensitive sampled every 80 ns

digitized by 6 TPDs





Experimental Setup

- KEK-PS π2 beam line
 - mainly 4 GeV π^-
- Superconducting magnet (JACEE)
 - B = 0, 0.5 and 1T
- Gas
 - Ar + isobutane (95:5)
- Drift field :
 - mainly 220 V/cm





Mesh readout

Calibration with a ⁵⁵Fe source installed inside the chamber.

Mesh readout by a Multichannel Analyser. Used for monitoring the gain



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June 2005 tests in KEK

December to May : design and build the Micromegas endplate, all from drawings and photographs of the GEM endplate.

June 4th,5th : assemble, test, install in Cryo-hall. Detect a leak. Re-glue the pad plane



June 6th : Re-assemble, test with ⁵⁵Fe in Ar+5%isobutane, OK, connect pad electronics. See tracks! Take data overnight

June 7th-10th : Take cosmic data

June 21st : Set last resistor value for E field continuity. Move to beam hall

June 22nd to 25th : setup DAQ (with 380 channels) during machine studies

June 26th, O:OO : start beam DAQ.

July 1st : end of beam, end-of-run party and analysis meeting...

B=0T



B=0.5 T



Charge Distribution

B = 1T, row by row



Drift velocity measurement



Using a beam at 45 deg. Look at time distribution on one pad. Max time gives drift time over 26.08+-0.02 cm



Time distributions



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Result

Avoid side pads where the field might not be nominal.

Padrow 6: 5.907 μs Padrow 7: 5.911 μs Padrow 8: 5.911 μs Padrow 9: 5.901 μs

Average 5.907 +-30 ns Trigger cable delay (measured): 310+-5 ns Trig. Logic and start TPD (guess) : 20+-20 ns

Total time 6.237+- 0.050 µs

 \rightarrow Velocity = 4.181+-0.034 (t meas)+-0.003 (length) cm/µs



Pad Response Function

evaluated by the charge fraction (NQ_i = Q_i/ Σ Q) on pad i, as a function of (X_{pad} - X_{track})



Charge width for different z drift regions (B = OT)



Width increases with drift distance (diffusion)

cathode

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Width of Pad Response Function as a function of z

Preliminary results

B = 0.5T

$$C_D = 293. \pm 4.[\mu m]$$

= 285(Magboltz)

B = 1T
$$C_D = 188. \pm 17. [\mu m]$$

- 193(Magboltz)

Width of pad response (All row) $\sigma_{PR}^2 \left\{mm^2\right\}$ x2= 52.4 / n.d.f.= 12 microM, Ar+Isobutzne, 0.0T.&=0" 430 ± 4 [μm / √cm], σ_{pec}(0) = 747 ± 34.4 [μm] $\sigma^2 = \sigma_{pp} \left(0 \right)^2 + C_p^2 z$ Drift distance [mm] opr [mm] y2=12.8 / n.df.= 10 Έ microM, Ar+Isobutzne, 0.5T, 4=0* 293 ± 3.54 [μm / ycm], σ_m(0)= 687 ± 25.1 [μm] $\sigma^2 = \sigma_{\rm DR}(0)\mathbf{\tilde{j}} + C_{\rm D}^2 \mathbf{z}$





Measured C_D in good agreement with Magboltz Simulation^{Prift distance [mm]}

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X Resolution vs Z

Use 8 rows, fix $\rm C_{d^{\prime}}$ and fit:

$$\sigma_x^2 = \sigma_0^2 + \frac{Cd^2 \cdot z}{N_{eff}}$$

N_{eff} ~ 35, much smaller than the average number of electrons (63 for 6.3 mm)

 $2.3mm / \sqrt{12}$

Preliminary results

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18



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Distortions

X Residual Mean and r.m.s. vs PadRows

Mean







r.m.s.



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Conclusions

- Micromegas tests went very smoothly (first 'pad partout' Micromegas TPC)
- Provided a lot of accurate and clean data on diffusion, resolution, etc...
- Much work remains for understanding σ_0 , N_{eff}, etc
- Next step (October) : study the effect of a resistive foil on resolution, with 2 setups
 - The same, with a resistive foil added
 - The Carleton TPC, with a new 128 pad endplate and special electronics.
- Very nice beginning of a world-wide